NSN 6625-00-159-2263

Fiig: T228-a

Semiconductor Device Test Set - Page 1 of 1



View Online at https://aerobasegroup.com/nsn/6625-00-159-2263 Width: 7.000 inches Length: 6.500 inches Dc Voltage Rating: 9.0 volts **Major Components:** Test leads **Accessory Component Quantity:** Joint Electronics Type Designation System Item Name: Test set, transistor Joint Electronics Type Designation System Item Type Number: Ts-1836c/u **Electrical Power Source Relationship:** Operating **Internal Battery Accommodation:** Included **Material And Location:** Plastic carrying case **Inclosure Feature:** Single item w/carrying case **Test Type For Which Designed:** Transistor beta; electrode resistance and current; field effect transistor, diode and rectifier **Operating Test Capability:** Beta test range 1 to 100 porm 5 pct out of circuit, 10 to 1000 porm 5 pct in circuit, 1 to 100 porm 10 pct 500 ohm load emitter to base, 10 to 1000 porm 10 pct 500 ohm load emitter to base; electrode resistance range 0 to 5000 porm 5 pct emitter to base, 0 to 5000 porm 5 pct collector to base, 0 to 5000 porm 5 pct collector to emmitter; electrode current range 0 to 100 ua porm 3 pct full scale collector cut off emitter open, 0 to 1 ma porm 3 pct full scale; collector cut off emitter open; fieldeffect transistor gain maximum or min range 0 to 2500 micromhosporm 5 pct out ofcircuit, 0 to 2500 micromhos porm 10 pct in circuit; gate source load 100 ohms; drain source load 4000 ohm; diode current range 0 to 100 ua porm 3 pct full scale, 0 to 1 ma porm 3 pct full scale; diode reverse to forward ratio 1, 10 porm 5 pct Height: 8.500 inches Shelf Life: N/a **Unit Of Measure: Demilitarization:** Yes - demil/mli